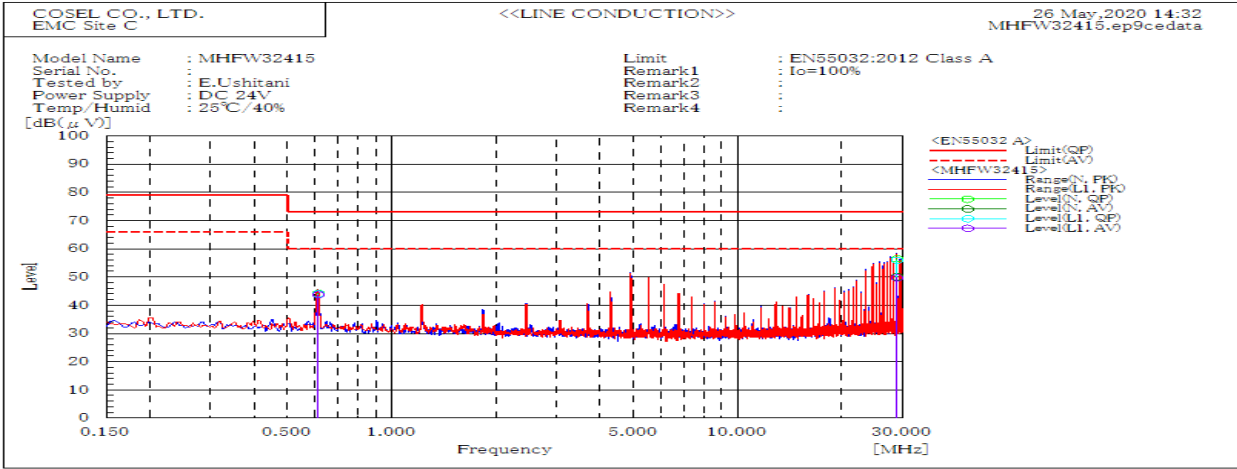
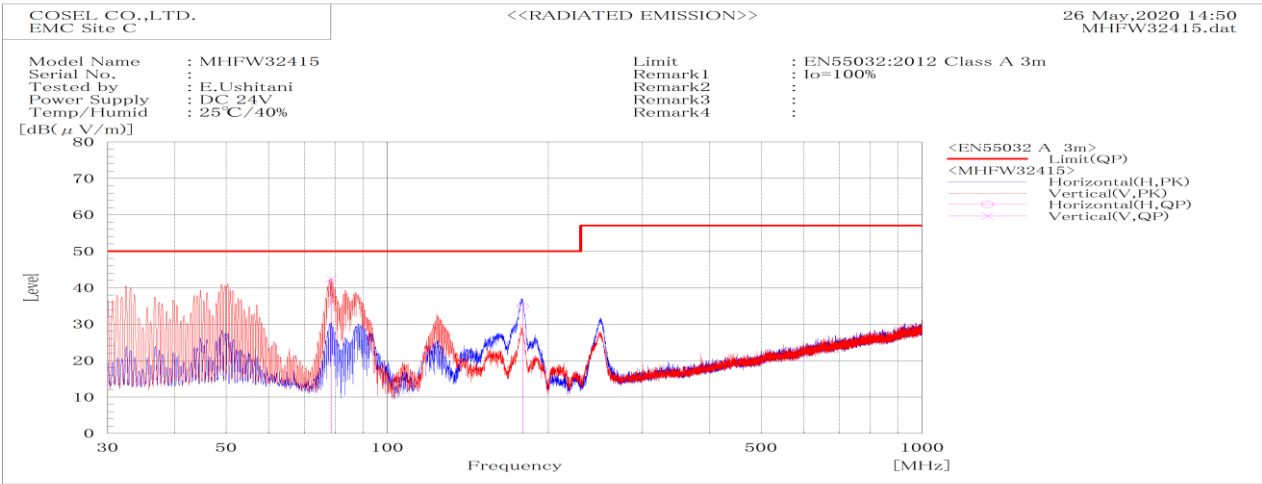


DATA SHEET		Date	08-Jun-20
Model	MHFW32415	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	E.Ushitani



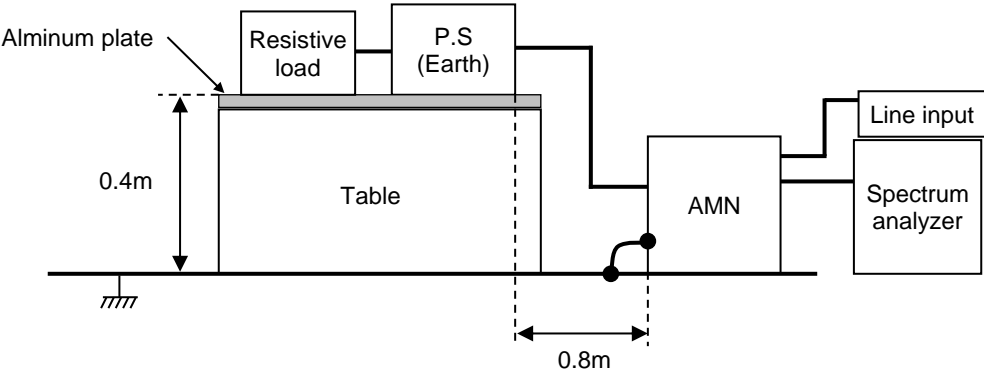
Frequency	Line	Level		Limit		Margin		Pass/Fail	Remark
MHz		dB(μV)		dB(μV)		dB			
		QP	AV	QP	AV	QP	AV		
0.613	L1	44	43.8	73	60	29	16.2	Pass	
28.815	L1	55.9	49.7	73	60	17.1	10.3	Pass	
0.613	N	44.1	43.9	73	60	28.9	16.1	Pass	
28.817	N	56.5	50.1	73	60	16.5	9.9	Pass	



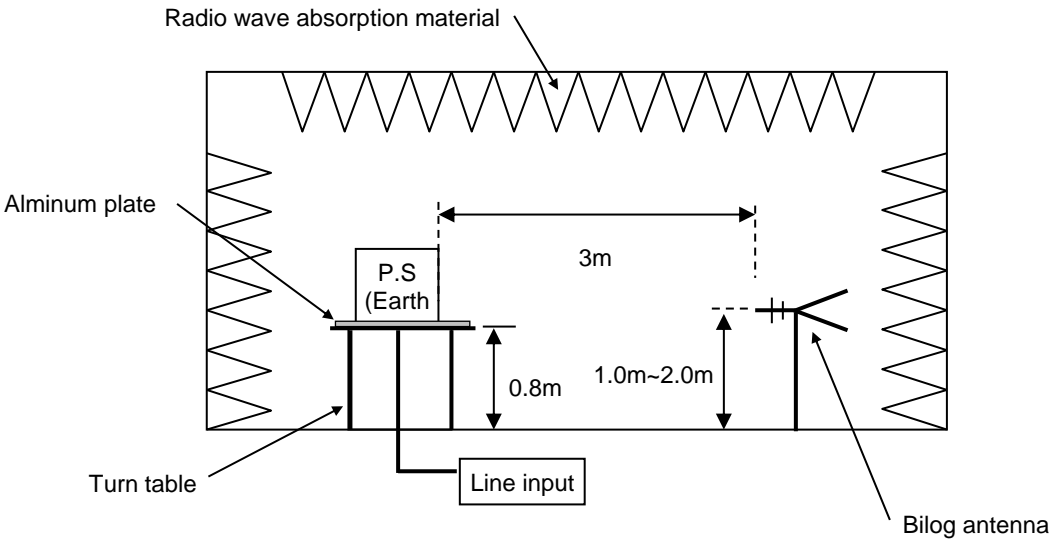
Frequency MHz	Polarization	Stability	Level	Limit	Margin	Pass/Fail	Height cm	Angle deg	Remark
			dB(uV/m) QP	dB(uV/m) QP	dB QP				
78.546	V	Stable	42.5	50	7.5	Pass	100	232.5	
179.199	H	Stable	34.9	50	15.1	Pass	198.3	4.5	

DATA SHEET		Date	08-Jun-20
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	E.Ushitani

1. Line conduction



2. Radiated emission

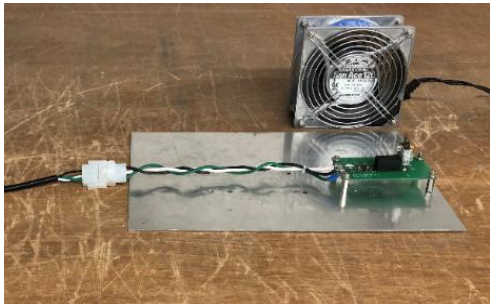


Conditions

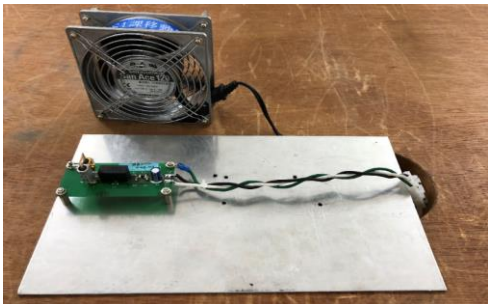
Test : EMI
Model Name: MHFW3□□

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

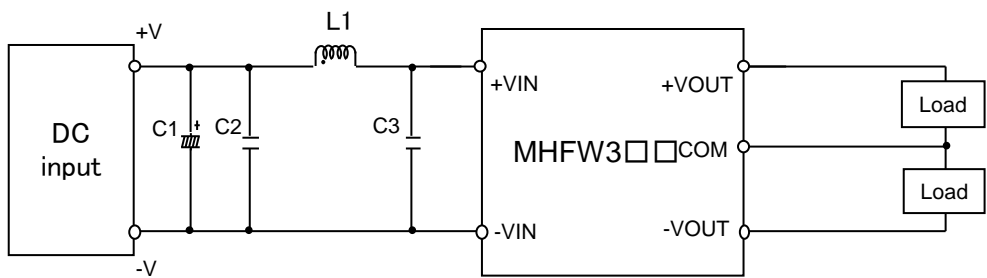


Fig.1 Testing circuitry

C1 :	MHFW312□□	50V 100μ F Electric capacitor (LXZseries NIPPON CHEMI-CON)
	MHFW324□□	—
	MHFW348□□	—
C2 :	MHFW312□□	25V 10μ F Ceramic capacitor (GRM31CR71E106K MURATA MANUFACTURING)
	MHFW324□□	50V 4.7μ F Ceramic capacitor (GRM31CR71H475K MURATA MANUFACTURING)
	MHFW348□□	100V 2.2μ F Ceramic capacitor (HMK316AC7225KLHTE TAIYO YUDEN)
C3 :	MHFW312□□	25V 10μ F Ceramic capacitor (GRM31CR71E106K MURATA MANUFACTURING)
	MHFW324□□	50V 4.7μ F Ceramic capacitor (GRM31CR71H475K MURATA MANUFACTURING)
	MHFW348□□	100V 2.2μ F Ceramic capacitor (HMK316AC7225KLHTE TAIYO YUDEN)
L1 :	MHFW312□□	1200mA 4.7μ H Inductor(LQH32PN4R7NNCL MURATA MANUFACTURING)
	MHFW324□□	900mA 10μ H Inductor(LQH32PN100MNCL MURATA MANUFACTURING)
	MHFW348□□	550mA 22μ H Inductor(LQH32PN220MNCL MURATA MANUFACTURING)